

### DESCRIPTION

These monolithic J-K flip-flops are negative-edge-triggered. The AND-OR gate inputs are inhibited while the clock input is low; when the clock goes high, the inputs are enabled and data will be accepted. Logical state of J and K inputs may be allowed to change when the clock pulse is in a high state and bistable-will perform according to the truth table as long as minimum setup times are observed. Input data are transferred to the outputs on the negative edge of the clock pulse.

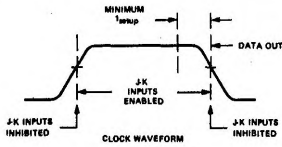
### TRUTH TABLE

$t_n$		$t_{n+1}$	
J	K	Q	$\bar{Q}$
0	0	$Q_n$	0
0	1	0	1
1	0	1	0
1	1	1	$\bar{Q}_n$

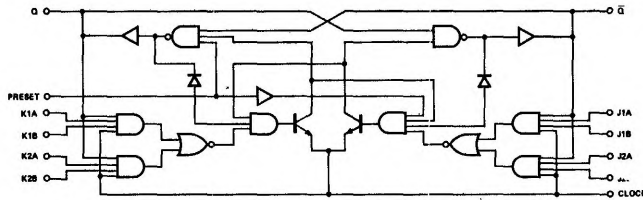
#### NOTES:

- $J = (J1A \oplus J1B) + (J2A \oplus J2B)$
- $K = (K1A \oplus K1B) + (K2A \oplus K2B)$
- $t_n$  = Bit time before clock pulse
- $t_{n+1}$  = Bit time after clock pulse

### CLOCK WAVEFORM

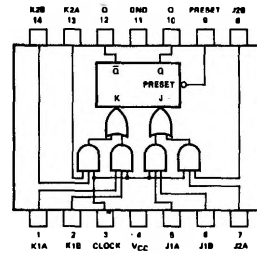


### LOGIC DIAGRAM

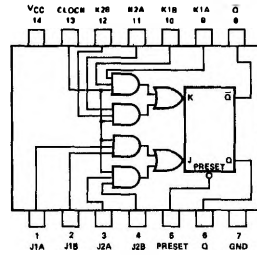


### PIN CONFIGURATIONS

#### W PACKAGE



#### A,F PACKAGE



# DIGITAL 54/74 TTL SERIES ■ S54H101, N74H101

## RECOMMENDED OPERATING CONDITIONS

	MIN	NOM	MAX	UNIT
Supply Voltage $V_{CC}$ : S54H101 Circuits	4.5	5	5.5	V
N74H101 Circuits	4.75	5	5.25	V
Operating Free-Air Temperature Range, $T_A$ : S54H101 Circuits	-55	25	125	°C
N74H101 Circuits	0	25	70	°C
Normalized Fan-Out from each Output, N			10	
Width of Clock Pulse, $t_p(\text{clock})$	10			ns
Width of Preset Pulse, $t_p(\text{preset})$	16			ns
Input Setup Time, $t_{\text{setup}}$ (See Above): Logical 1	10			ns
Logical 0	13			ns
Input Hold Time, $t_{\text{hold}}$	0			ns
Clock Pulse Transition Time, $t_0$			150	ns

## ELECTRICAL CHARACTERISTICS (over recommended operating free-air temperature range unless otherwise noted)

PARAMETER	TEST CONDITIONS*	MIN	TYP†	MAX	UNIT
$V_{in(1)}$ Input voltage required to ensure logical 1 at any input terminal		2			V
$V_{in(0)}$ Input voltage required to ensure logical 0 at any input terminal				0.8	V
$V_{out(1)}$ Logical 1 output voltage	$V_{CC} = \text{MIN}, I_{\text{load}} = -500\mu\text{A}$	2.4	3.2		V
$V_{out(0)}$ Logical 0 output voltage	$V_{CC} = \text{MIN}, I_{\text{sink}} = 20 \text{ mA}$		0.25	0.4	V
$I_{in(0)}$ Logical 0 level input current at J1A, J1B, J2A, J2B, K1A, K1B, K2A, K2B, or preset	$V_{CC} = \text{MAX}, V_{in} = 0.4 \text{ V}$		-1	-2	mA
$I_{in(0)}$ Logical 0 level input current at clock	$V_{CC} = \text{MAX}, V_{in} = 0.4 \text{ V}$		-3	-4.8	mA
$I_{in(1)}$ Logical 1 level input current at J or K	$V_{CC} = \text{MAX}, V_{in} = 2.4 \text{ V}$			50	$\mu\text{A}$
	$V_{CC} = \text{MAX}, V_{in} = 5.5 \text{ V}$			1	mA
$I_{in(1)}$ Logical 1 level input current at preset	$V_{CC} = \text{MAX}, V_{in} = 2.4 \text{ V}$			100	$\mu\text{A}$
	$V_{CC} = \text{MAX}, V_{in} = 5.5 \text{ V}$			1	mA
$I_{in(1)}$ Logical 1 level input current at clock	$V_{CC} = \text{MAX}, V_{in} = 2.4 \text{ V}$	0		-1	mA
	$V_{CC} = \text{MAX}, V_{in} = 5.5 \text{ V}$			1	mA
$I_{OS}$ Short-circuit output current**	$V_{CC} = \text{MAX}, V_{in} = 0$	-40		-100	mA
$I_{CC}$ Supply current	$V_{CC} = \text{MAX}$		20	38	mA

## SWITCHING CHARACTERISTICS, $V_{CC} = 5\text{V}, T_A = 25^\circ\text{C}, N = 10$

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$f_{\text{clock}}$ Maximum input clock frequency	$C_L = 25 \text{ pF}, R_L = 280 \Omega$	40	50		MHz
$t_{pd1}$ Propagation delay time to logical 1 level from preset to output	$C_L = 25 \text{ pF}, R_L = 280 \Omega$		8	12	ns
$t_{pd0}$ Propagation delay time to logical 0 level from preset to output (clock low)	$C_L = 25 \text{ pF}, R_L = 280 \Omega$		23	35	ns
$t_{pd0}$ Propagation delay time to logical 0 level from preset to output (clock high)	$C_L = 25 \text{ pF}, R_L = 280 \Omega$		15	20	ns
$t_{pd1}$ Propagation delay time to logical 1 level from clock to output	$C_L = 25 \text{ pF}, R_L = 280 \Omega$	5	10	15	ns
$t_{pd0}$ Propagation delay time to logical 0 level from clock to output	$C_L = 25 \text{ pF}, R_L = 280 \Omega$	8	16	20	ns

\* For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type.

\*\* Not more than one output should be shorted at a time, and duration of short-circuit test should not exceed 1 second.

† All typical values are at  $V_{CC} = 5\text{V}, T_A = 25^\circ\text{C}$ .